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Please note: As part of the Fairchild Semiconductor integration, some of the Fairchild orderable part numbers will need to change in order to meet ON Semiconductor's system requirements. Since the ON Semiconductor product management systems do not have the ability to manage part nomenclature that utilizes an underscore (_), the underscore (_) in the Fairchild part numbers will be changed to a dash (-). This document may contain device numbers with an underscore (_). Please check the ON Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at www.onsemi.com. Please email any questions regarding the system integration to Fairchild guestions@onsemi.com.

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October 2013

FGB3236_F085 / FGI3236_F085

EcoSPARK÷ 320mJ, 360V, N-Channel Ignition IGBT

Features

- Industry Standard D²-Pak package
- SCIS Energy = 320mJ at T_J = 25°C
- Logic Level Gate Drive
- Qualified to AEC Q101
- RoHS Compliant

Applications

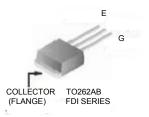
- Automotive Ignition Coil Driver Circuits
- Coil On Plug Applications



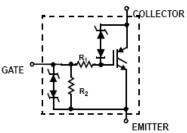
Package



JEDEC TO-263AB D²-Pak



Symbol



Device Maximum Ratings $T_A = 25^{\circ}C$ unless otherwise noted

| Symbol | Parameter | Ratings | Units |
|---------------------|---|-------------|-------|
| BV _{CER} | Collector to Emitter Breakdown Voltage (I _C = 1mA) | 360 | V |
| BV _{ECS} | Emitter to Collector Voltage - Reverse Battery Condition (I _C = 10mA) | 24 | V |
| E _{SCIS25} | Self Clamping Inductive Switching Energy ($I_{SCIS} = 14.7A, L = 3.0 \text{mHy}, T_J = 25^{\circ}\text{C}$) | 320 | mJ |
| | Self Clamping Inductive Switching Energy ($I_{SCIS} = 10.4A$, L = 3.0mHy, $T_J = 150$ °C) | 160 | mJ |
| I _{C25} | Collector Current Continuous, at V _{GE} = 4.0V, T _C = 25°C | 44 | Α |
| I _{C110} | Collector Current Continuous, at V _{GE} = 4.0V, T _C = 110°C | 27 | Α |
| V_{GEM} | Gate to Emitter Voltage Continuous | ±10 | V |
| D | Power Dissipation Total, at T _C = 25°C | 187 | W |
| P_{D} | Power Dissipation Derating, for T _C > 25°C | 1.25 | W/°C |
| T _J | Operating Junction Temperature Range | -40 to +175 | °C |
| T _{STG} | Storage Junction Temperature Range | -40 to +175 | °C |
| T _L | Max. Lead Temp. for Soldering (Leads at 1.6mm from case for 10s) | 300 | °C |
| T _{PKG} | T _{PKG} Max. Lead Temp. for Soldering (Package Body for 10s) | | °C |
| ESD | Electrostatic Discharge Voltage at 100 pF, 1500 Ω | 4 | kV |

Package Marking and Ordering Information

| Device Marking | Device | Package | Reel Size | Tape Width | Quantity |
|----------------|--------------|---------|-----------|------------|-----------|
| FGB3236 | FGB3236_F085 | TO263 | 330mm | 24mm | 800 units |
| FGI3236 | FGI3236_F085 | TO262 | Tube | NA | 50 units |

Electrical Characteristics $T_A = 25^{\circ}C$ unless otherwise noted

| | Symbol | Parameter | Test Conditions | Min | Тур | Max | Units | |
|--|--------|-----------|-----------------|-----|-----|-----|-------|--|
|--|--------|-----------|-----------------|-----|-----|-----|-------|--|

Off State Characteristics

| BV _{CER} | Collector to Emitter Breakdown Voltage | $I_{CE} = 2\text{mA}, V_{GE} = 0,$ $R_{GE} = 1\text{K}\Omega, \text{ See Fig. 15}$ $T_{.I} = -40 \text{ to } 150^{\circ}\text{C}$ | | 330 | 363 | 390 | ٧ |
|-------------------|--|---|----------------------------------|-----|-----|-----|----|
| BV _{CES} | Collector to Emitter Breakdown Voltage | $I_{CE} = 10 \text{mA}, V_{GE} = 0 \text{V},$ $R_{GE} = 0,$ $T_{J} = -40 \text{ to } 150^{\circ}\text{C}$ | | 350 | 378 | 410 | ٧ |
| BV _{ECS} | Emitter to Collector Breakdown Voltage | I_{CE} = -75mA, V_{GE} = 0V, T_{C} = 25°C | | 30 | - | 1 | V |
| BV_{GES} | Gate to Emitter Breakdown Voltage | $I_{GES} = \pm 2mA$ | | ±12 | ±14 | - | V |
| 1 | Collector to Emitter Leakage Current | V _{CES} = 250V, | $T_{\rm C} = 25^{\rm o}{\rm C}$ | 1 | 1 | 25 | μΑ |
| ICES | Collector to Emitter Leakage Current | See Fig. 11 | $T_{\rm C} = 150^{\rm o}{\rm C}$ | - | - | 1 | mA |
| 1 | Emitter to Collector Leakage Current | V _{EC} = 24V, | $T_{\rm C} = 25^{\rm o}{\rm C}$ | - | - | 1 | mA |
| IECS | Emilier to Collector Leakage Current | See Fig.11 | $T_{\rm C} = 150^{\rm o}{\rm C}$ | - | - | 40 | MA |
| R ₁ | Series Gate Resistance | | | - | 100 | - | Ω |
| R ₂ | Gate to Emitter Resistance | | | 10K | - | 30K | Ω |

On State Characteristics

| V _{CE(SAT)} | Collector to Emitter Saturation Voltage | I _{CE} = 6A, V _{GE} = 4V, | T _C =25°C, See Fig. 3 | 1 | 1.14 | 1.4 | V |
|----------------------|---|--|---------------------------------------|----|------|------|---|
| V _{CE(SAT)} | Collector to Emitter Saturation Voltage | I _{CE} = 10A, V _{GE} = 4.5V, | T _C = 150°C, See Fig. 4 | - | 1.32 | 1.7 | V |
| V _{CE(SAT)} | Collector to Emitter Saturation Voltage | I _{CE} = 15A, V _{GE} = 4.5V, | $T_{\rm C} = 150^{\rm o}{\rm C}$ | - | 1.61 | 2.05 | V |
| I _{CE(ON)} | Collector to Emitter On State Current | V_{GE} = 5V, V_{CE} = 5V | | 50 | - | - | Α |

Max Units

Min

Electrical Characteristics $T_A = 25^{\circ}C$ unless otherwise noted

Parameter

| Dynamic Characteristics | | | | | | | | | |
|-------------------------|-----------------------------------|---|----------------------------------|------|-----|-----|----|--|--|
| Q _{G(ON)} | Gate Charge | I _{CE} = 10A, V _{CE} = 12V, V _{GE} = 5V, See Fig.14 | | - | 20 | - | nC | | |
| \/ · | Gate to Emitter Threshold Voltage | I _{CE} = 1mA, V _{CE} = V _{GE} | $T_{\rm C} = 25^{\rm o}{\rm C}$ | 1.3 | 1.6 | 2.2 | V | | |
| $V_{GE(TH)}$ | Gate to Emitter Threshold Voltage | See Fig. 10 | $T_{\rm C} = 150^{\rm o}{\rm C}$ | 0.75 | 1.1 | 1.8 | V | | |
| V_{GEP} | Gate to Emitter Plateau Voltage | V _{CE} = 12V, I _{CE} = 10A | | - | 2.6 | - | V | | |

Test Conditions

Switching Characteristics

Symbol

| t _{d(ON)R} | Current Turn-On Delay Time-Resistive | 02 | - | 0.65 | 4 | μS |
|----------------------|---------------------------------------|---|---|------|-----|----|
| t_{rR} | Current Rise Time-Resistive | $V_{GE} = 5V, R_G = 1K\Omega$ $T_J = 25^{\circ}C, See Fig.12$ | - | 1.7 | 7 | μS |
| t _{d(OFF)L} | Current Turn-Off Delay Time-Inductive | V_{CE} = 300V, L = 500 μ Hy, | - | 5.4 | 15 | μS |
| t _{fL} | Current Fall Time-Inductive | $V_{GE} = 5V, R_G = 1K\Omega$ $T_J = 25^{\circ}C, See Fig.12$ | - | 1.64 | 15 | μS |
| SCIS | Self Clamped inductive Switching | $T_J = 25^{\circ}\text{C}$, L = 3.0mHy, $I_{CE} = 14.7\text{A}$, $R_G = 1\text{K}\Omega$, $V_{GE} = 5\text{V}$, See Fig.1&2 | - | - | 320 | mJ |

Thermal Characteristics

| R_{θ} | IC | Thermal Resistance Junction to Case | All Packages | - | - | 0.8 | °C/W |
|--------------|----|-------------------------------------|--------------|---|---|-----|------|
| U | 30 | | 3 3 | | | | |

Typical Performance Curves

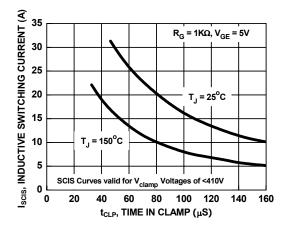
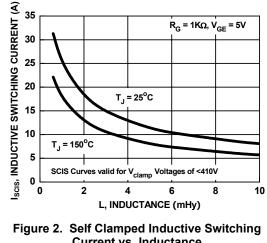


Figure 1. Self Clamped Inductive Switching Current vs. Time in Clamp



Current vs. Inductance

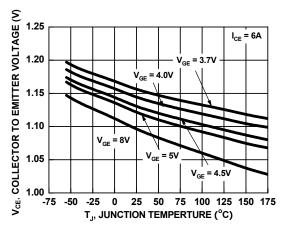


Figure 3. Collector to Emitter On-State Voltage vs. Junction Temperature

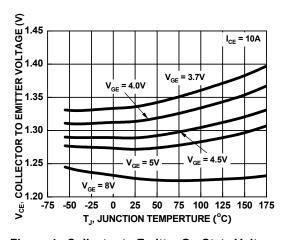


Figure 4. Collector to Emitter On-State Voltage vs. Junction Temperature

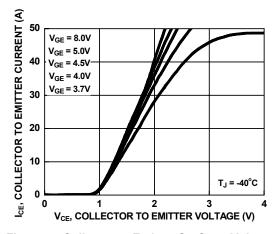


Figure 5. Collector to Emitter On-State Voltage vs. Collector Current

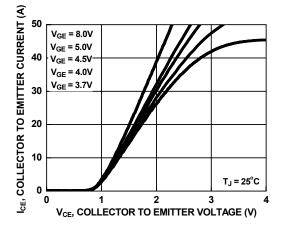


Figure 6. Collector to Emitter On-State Voltage vs. Collector Current

Typical Performance Curves (Continued)

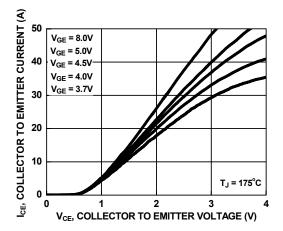


Figure 7. Collector to Emitter On-State Voltage vs. Collector Current

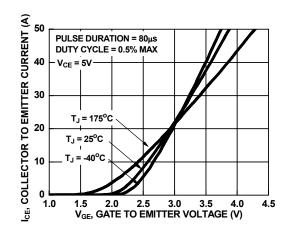


Figure 8. Transfer Characteristics

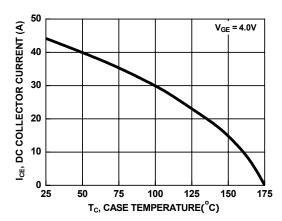


Figure 9. DC Collector Current vs. Case Temperature

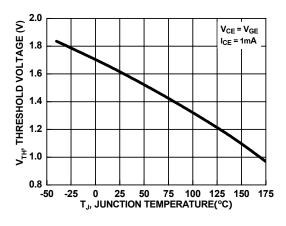


Figure 10. Threshold Voltage vs. Junction Temperature

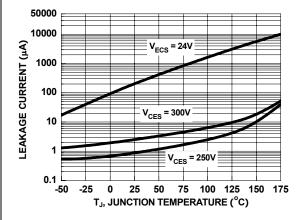


Figure 11. Leakage Current vs. Junction Temperature

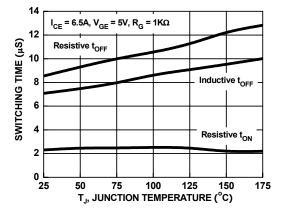


Figure 12. Switching Time vs. Junction Temperature

Typical Performance Curves (Continued)

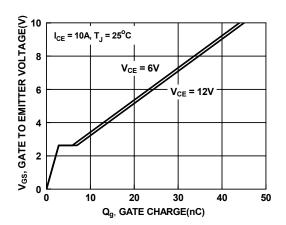


Figure 13. Capacitance vs. Collector to Emitter Voltage

Figure 14. Gate Charge

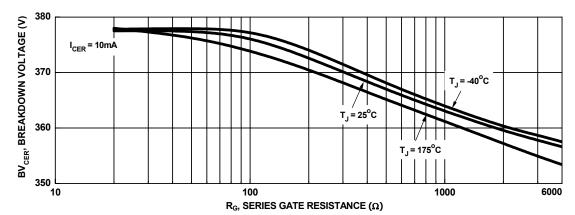


Figure 15. Break Down Voltage vs. Series Gate Resistance

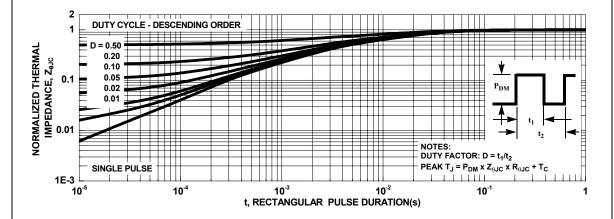


Figure 16. IGBT Normalized Transient Thermal Impedance, Junction to Case

Test Circuit and Waveforms

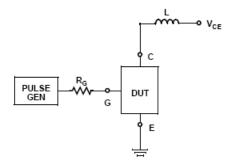


Figure 17. Inductive Switching Test Circuit

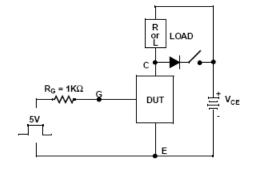


Figure 18. t_{ON} and t_{OFF} Switching Test Circuit

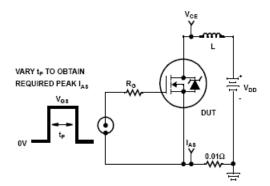


Figure 19. Energy Test Circuit

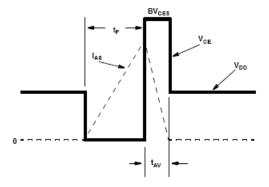
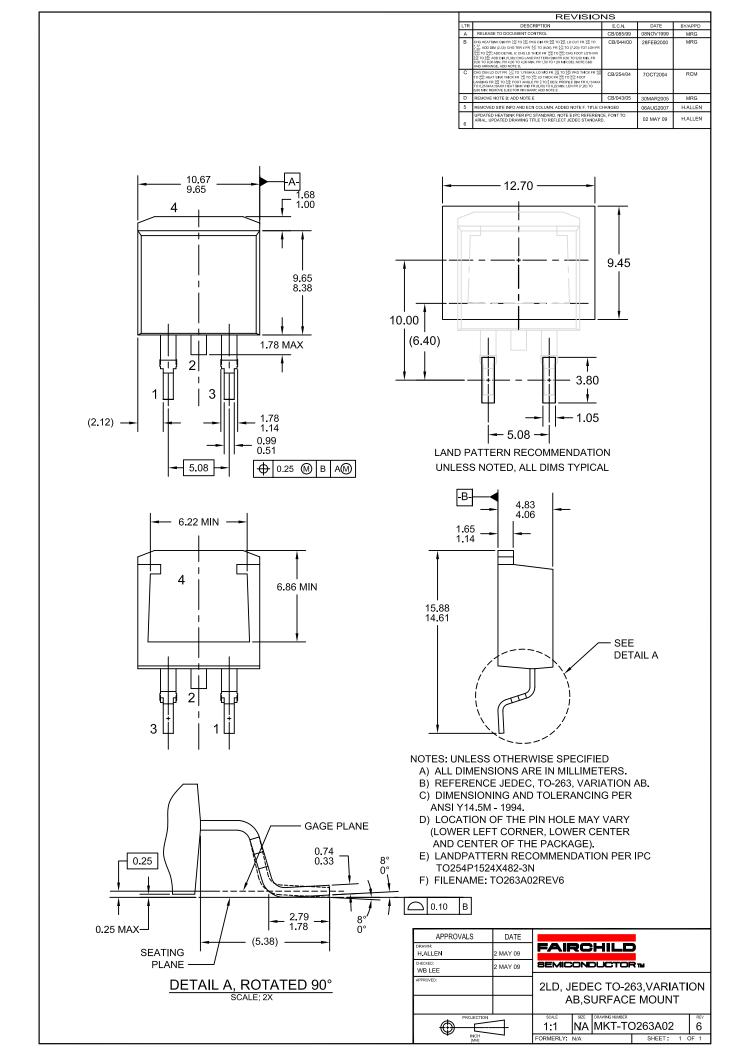
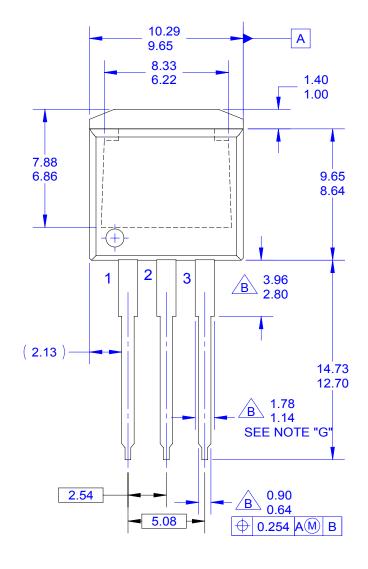
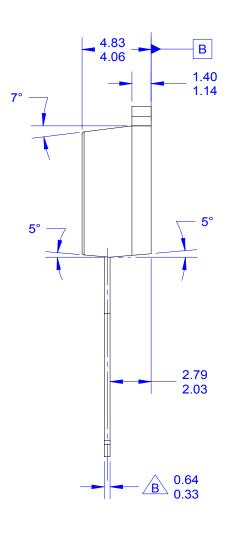


Figure 20. Energy Waveforms



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NOTES:

A. EXCEPT WHERE NOTED CONFORMS TO
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B DOES NOT COMPLY JEDEC STD. VALUE.
C. ALL DIMENSIONS ARE IN MILLIMETERS.
D. DIMENSIONS ARE EXCLUSIVE OF BURRS,
MOLD FLASH AND TIE BAR PROTRUSIONS.
E. DIMENSION AND TOLERANCE AS PER ANSI
V14 5-1904

F. LOCATION OF PIN HOLE MAY VARY
(LOWER LEFT CORNER, LOWER CENTER
AND CENTER OF PACKAGE)
G. MAXIMUM WIDTH FOR F102 DEVICE = 1.35 MAX.

H. DRAWING FILE NAME: TO262A03REV5

| | APPROVALS | DATE | | | | | | |
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